John F. Schneider  
Journal Articles and Technical Reports


Selected Conference Presentations


2. Solid Phase Microextraction (SPME) with GC/MS and GC/matrix isolation-IR Analysis in the Identification of Volatile Organic Compounds in Food Products, John F. Schneider, 227th American Chemical Society National Meeting, Anaheim, CA, 2004

3. The Evolution of On-Site Analysis Over the Last 20 Years, John F. Schneider, International On-Site Analysis Conference, San Diego, CA, 2002


7. Solid Phase Microextraction (SPME) screening for Chemical Warfare Agents, John F. Schneider, Pacificchem 2000, Honolulu, HI, 2000


10. Portable X-Ray Fluorescence for the Determination of Heavy Metal Contamination in Soil on Firing Ranges, John F. Schneider, M. Hahn, J. Lee, and A. Bohn, Pittsburgh Conference, Chicago, IL 1996


John F. Schneider

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Education

- M.S. Analytical Chemistry, Northern Illinois University
- B.S. Chemistry, Elmhurst College

Biography

John F. Schneider is the Group Leader of the Chemical Analysis and Research Group of The Materials Science Division of Argonne National Laboratory. The Group is involved in chemical detection, analytical chemistry method development, the development of Tera Hertz sources for standoff detection, the development of neutron activation for the characterization of materials inside containers, instrumental analysis, method validation, and basic chemical research. The Group is currently heavily involved in projects for the Office of Naval Research (ONR) His technical interests include, chemical sensor and sensor array development, field analytical chemistry, gas chromatography (GC), GC/IR, GC/MS, Solid Phase Microextraction (SPME), Chemical warfare agent analysis, and X-ray Fluorescence analysis for metals in the field.